Dear Reviewer,

Thanks a lot for the comments and excuse me for not being clear enough. I heeded all you comments and tried to clarify the issues.

- 1. "what is a "schubweg"? Please add parenthesis as you did in the talk and write something like "mean drift path before trapping" or similar."
- →→→ After such a large dose, all detector materials become trap limited with a schubweg, the average drift distance before a free charge carrier gets trapped, below 75 µm.
 - 2. "L56: explain "in the fiducial area". Put your sentence "A constant fiducial region was used to minimise any effects of the spatial dependence." from section 3.2. to 2.2. already."
- →→→ The preliminary beam test results show that, relative to a planar silicon device, the efficiency in the fiducial area was 99.3 % (Figure 3a). The fiducial area was selected such as to exclude non-working 3D cells found by visual inspection, which can happen due to broken or missing columns or due to metalisation issues.

with kind regards,
Michael Reichmann